



A Review of material properties of MoSe_2 layered compound semiconductors useful for Photo electrochemical solar cells

D.K.BHOI

Hemchandracharya North Gujarat University, Patan
M.N.College, Visnagar

Abstract:

Molybdenum/tungsten dichalcogenides constitute a well-defined family of compounds which crystallize in a layer-type structure. These compounds have properties tailored for use as storage electrodes in rechargeable photoelectrochemical solar energy storage cells. These compounds find a wide range of applications in the field of catalysis and as lubricants at high temperatures and pressures. The basic structural unit of such a compound is a sandwich of three planes: one plane of transition metal atoms between two halogen atoms. The material properties of the layered semiconductors, molybdenum diselenide (MoSe_2). Monolayer MoSe_2 is a direct band gap semiconductor which has been recently investigated for low-power field effect transistors.

Keywords: Dichalcogenide; Semiconducting Thin Film; Molybdenum Diselenide; Tungsten Diselenide; Molybdenum Tungsten Diselenide.

1. Introduction

As worldwide energy demands increase, conventional energy resources, such as fossil fuels, will be exhausted in the not-too-distant future. Therefore, we must develop and use alternative energy resources, especially our only long-term natural resource, the sun. The solar cell is considered as a major candidate for obtaining energy from the sun, since it can convert solar radiation directly to electricity with high conversion efficiency, it can provide nearly permanent power at low operating cost, and it is virtually free of pollution. For application in photovoltaic and photoelectrochemical (PEC) solar cells, semiconductor thin films such as CdSe, CdS, CdHgTe, GaAs, CuInSe₂, CuInS, CdTe, SrTiO₃, SnO₂, In₂O₃, TiO₂, SnSe, SnS, SnSSe, MoSe_2 and WSe₂ have been elaborately studied.

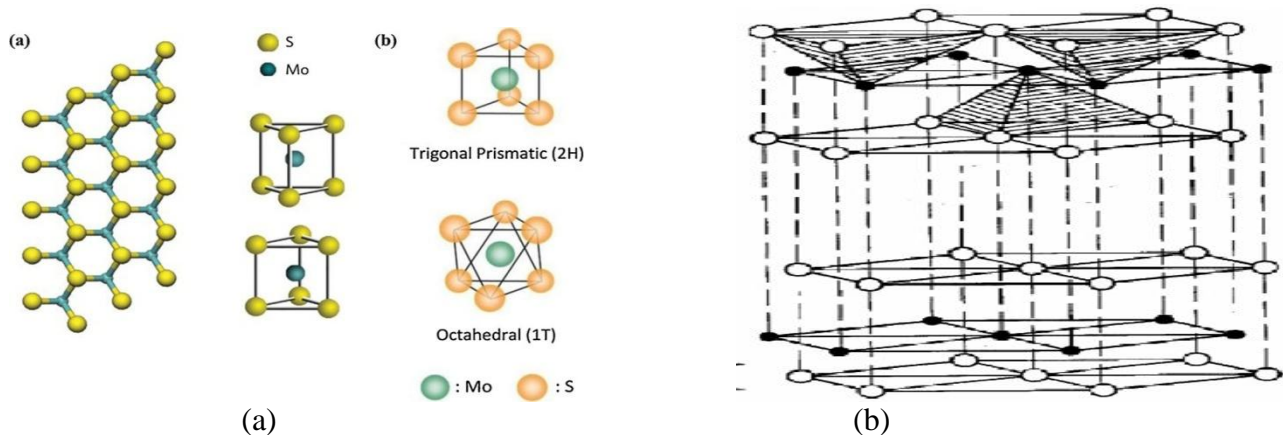


Figure:-1 (a) Few-layer MoSe_2 , (b) Crystal structure showing the (hkl) planes and Mo, Se locations.

2. Methods of Preparations

There are several methods for preparing thin films. Some of them are vacuum evaporation, sputtering, hot-wall epitaxy, spray pyrolysis, chemical vapour deposition, solution growth, electrodeposition, electrode-less deposition, brush plating, screen printing, pulse electrodeposition. A simple and brief discussion about the various methods of film preparation has been discussed by Behrndt. Among molybdenum chalcogenides, MoSe_2 has led to the best solid-state cells with efficiencies exceeding 6%, in particular due to the surprisingly large short-circuit currents of 33mAcm^{-2} . based on the better performance of electrochemical cells based on MoSe_2 exceeding the 10% efficiency limit. The conceptional difference between a conventional hetero interface and an interface fabricated via the Vander Waals epitaxy growth good reason for hope to achieve efficiencies well above 10% after these first attempts.

3. Material properties of MoSe_2

1	Type	p-type
2	Structure	Hexagonal with $a = 0.3285\text{nm}$ $b = 0.3285\text{nm}$ $c = 1.294\text{ nm}$
3	Indirect band gap (eV)	Polycrystalline 1.26
4	Carrier concentration (cm^{-3})	$3.3 \times 10^{16} - 7 \times 10^{18}$
5	Refractive index (n)	$n_a = 4.25$ (1 eV)
6	Resistivity (ohm-cm)	10^3
7	Effective mass of hole	$m_e^* \approx m_h^* \approx 0.5m_0$ (m_0 , free electron mass)
8	Dielectric constant (ϵ)	$\epsilon_{\perp} = 15.4$
9	Activation energy (eV)	0.08–0.57
10	Density of MoSe_2 (gm cm^{-3})	6.948
11	Melting point ($^{\circ}\text{C}$)	>1200
12	Stability	Stable

4. Result and Discussion

4.1 Surface characterization

The XRD peaks correspond to a hexagonal structure. The d-values evaluated for the dominant peaks having hexagonal structure using the JCPDS data for MoSe_2 . The lattice parameters are calculated to be $a=b= 3.210\text{A}^{\circ}$ and $c = 12.592\text{ A}^{\circ}$. From the lattice parameters and using Vegard's law, the composition of the film has been confirmed. The average grain size of these films varies in the range of 0.029–0.17 μm . The composition of the MoSe_2 film deposited at optimized conditions is recorded in the binding energy range from 0.00 to 20.00 keV. The intense peaks at 2.23, 1.85 and 1.70 keV confirm the elemental presence of Mo, W and Se and in the weight percentage values of 0.4077, 0.2803 and 0.0158 for MoSe_2 , and this is shown in Figure 2.

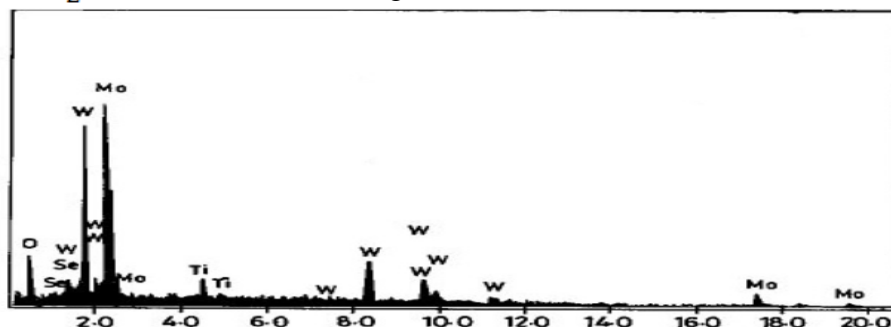


Figure-2 spectrum of MoSe_2 film

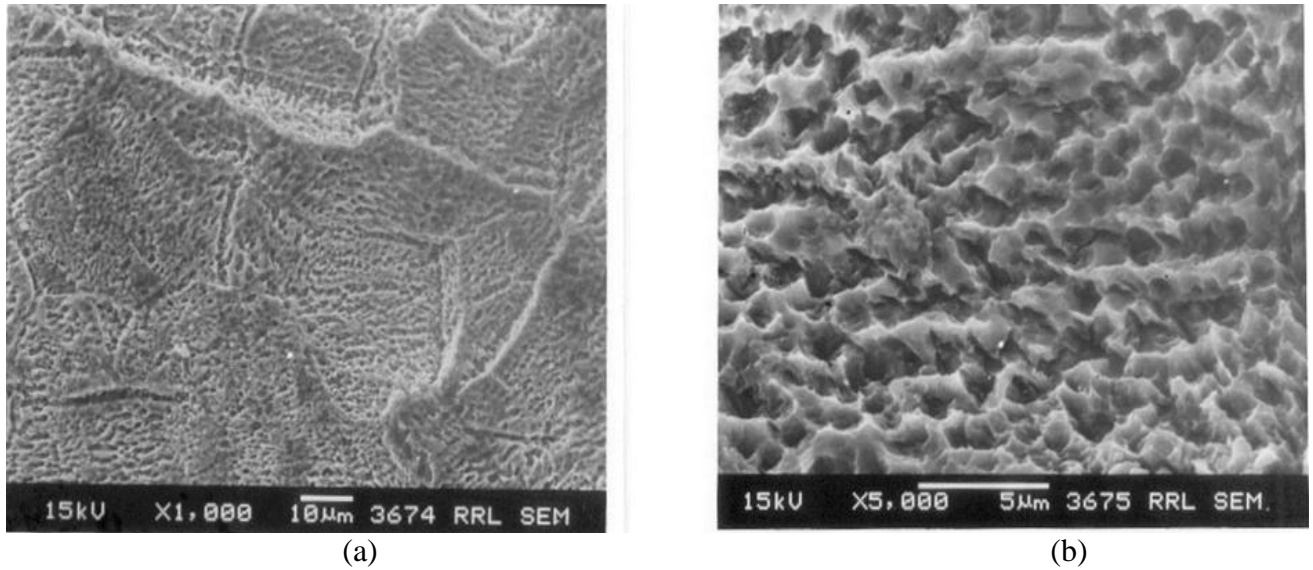


Figure-3 SEM micrograph of MoSe₂ film annealed at 15°C in vacuum with magnification

4.2 SEM studies of MoSe₂

The scanning electron micrograph of an as-deposited and annealed MoSe₂ film annealed in vacuum at 150°C for 1 h deposited on a titanium substrate is shown in Figure 3(a) and (b). The grain size for the as-deposited film is 0.841 μm and for the vacuum-annealed film is 0.940 μm.

4.3 Morphology of pulse electrodeposited MoSe₂ thin films

AFM images reveal that these films have a granular morphology. Irregular-shaped grains are seen. The AFM data are analysed by averaging the roughness of an area 5×5 μm² for various random positions on the sample surface in order to minimize the influence of local topography variation. Figure 5 shows a three-dimensional AFM image for an area of 5×5 μm² for MoSe₂ in the as-deposited film and annealed in vacuum at 150°C for 1 h, with a thickness of 1.0 μm. All the figures show the presence of high hills on the top of a homogeneous granular background surface. Both the density and the height of the hills increase with the thickness of the deposit. The perturbation scanned by the AFM is a measure of the crystallographic columnar size.

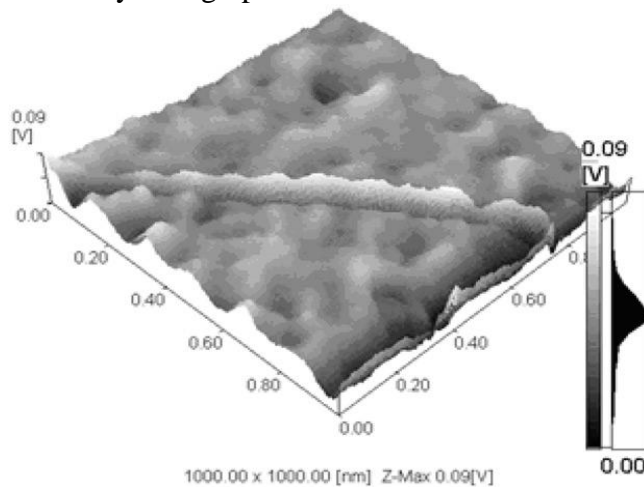


Figure-4 AFM image of MoSe₂ film

5. Conclusion

A survey on less expensive semiconducting molybdenum diselenide, tungsten diselenide and molybdenum tungsten diselenide was elaborately studied. The material properties of the films prepared using various deposition techniques are reported. The films prepared are mostly found to be polycrystalline in nature and show p- and n-type semiconducting nature. The structural, surface morphological and optical studies reveal that device quality semiconducting molybdenum / tungsten dichalcogenides can be prepared using pulse electrodeposition technique and used for PEC solar cells.

References

1. A.A Al-Hilli and B.L. Evans, J. Crystal Growth, 1972, 15, 93.
2. Barua, A.K. Thin Film Solar Technologies: Potential for Cost Reduction of Solar Photovoltaic Electricity. Indian J. Pure Appl. Phys. 1996, 34, 669–673.
3. Department of Materials Science & Engineering, The University of Texas at Dallas, Richardson, Texas 75080, USA
4. Department of Physics, The University of Texas at Dallas, Richardson, Texas 75080, USA
5. K. Hofmann, H.J. Lewerenz and C. Pettenkofer, Solar Energy Materials, 1988, 17, 165.
6. Koma, A. K. Sunouchi and T. Miyajima, Micro electron. Eng., 1984, 2, 129.
- A. _____. Vac.Sci. Technol. 1985, B3, 724.
7. Singh, J. Semiconductor Optoelectronic Devices; Physics and Technology; McGraw-Hill Inc:New York, 1995.
8. Tributsch, H. Strategies for Solar Cell Generation. Proc. Indian Acad. Sci. (Chem. Sci.) 1993.